


<b>Search Notes</b> 	<b>Application/Control No.</b> 10748168	<b>Applicant(s)/Patent Under Reexamination</b> KIM ET AL.
	<b>Examiner</b> YUWEN PAN	<b>Art Unit</b> 2618

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Class	Subclass	Date	Examiner

SEARCH NOTES		
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INTERFERENCE SEARCH			
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